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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	29880
Number of Logic Elements/Cells	382464
Total RAM Bits	28311552
Number of I/O	320
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vhx380t-2ffg1154c

Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on sequence and ramp rate of the power supply.

The recommended power-on sequence for Virtex-6 devices is V_{CCINT} , V_{CCAUX} , and V_{CCO} to meet the power-up current requirements listed in [Table 5](#). V_{CCINT} can be powered up or down at any time, but power up current specifications can vary from [Table 5](#). The device will have no physical damage or reliability concerns if V_{CCINT} , V_{CCAUX} , and V_{CCO} sequence cannot be followed.

If the recommended power-up sequence cannot be followed and the I/Os must remain 3-stated throughout configuration, then V_{CCAUX} must be powered prior to V_{CCO} or V_{CCAUX} and V_{CCO} must be powered by the same supply. Similarly, for power-down, the reverse V_{CCAUX} and V_{CCO} sequence is recommended if the I/Os are to remain 3-stated.

The GTH transceiver supplies must be powered using a MGTHAVCC, MGTHAVCCR, MGTHAVCCPLL, and MGTHAVTT sequence. There are no sequencing requirement for these supplies with respect to the other FPGA supply voltages. For more detail see [Table 27: GTH Transceiver Power Supply Sequencing](#). There are no sequencing requirements for the GTX transceivers power supplies.

[Table 5](#) shows the minimum current, in addition to I_{CCQ} , that are required by Virtex-6 devices for proper power-on and configuration. If the current minimums shown in [Table 4](#) and [Table 5](#) are met, the device powers on after all three supplies have passed through their power-on reset threshold voltages. The FPGA must be configured after applying V_{CCINT} , V_{CCAUX} , and V_{CCO} for the appropriate configuration banks. Once initialized and configured, use the XPE tools to estimate current drain on these supplies.

Table 5: Power-On Current for Virtex-6 Devices

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	Units
	Typ ⁽¹⁾	Typ ⁽¹⁾	Typ ⁽¹⁾	
XC6VLX75T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX195T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX365T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX760	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX250T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX255T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX380T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX565T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA
XQ6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

Table 6: Power Supply Ramp Time

Symbol	Description	Ramp Time	Units
V _{CCINT}	Internal supply voltage relative to GND	0.20 to 50.0	ms
V _{CCO}	Output drivers supply voltage relative to GND	0.20 to 50.0	ms
V _{CCAUX}	Auxiliary supply voltage relative to GND	0.20 to 50.0	ms

SelectIO™ DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 7: SelectIO DC Input and Output Levels

I/O Standard	V _{IL}		V _{IH}		V _{OL}	V _{OH}	I _{OL}	I _{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVCMOS25, LVDCI25	-0.3	0.7	1.7	V _{CCO} + 0.3	0.4	V _{CCO} - 0.4	Note(3)	Note(3)
LVCMOS18, LVDCI18	-0.3	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.3	0.45	V _{CCO} - 0.45	Note(4)	Note(4)
LVCMOS15, LVDCI15	-0.3	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.3	25% V _{CCO}	75% V _{CCO}	Note(4)	Note(4)
LVCMOS12	-0.3	35% V _{CCO}	65% V _{CCO}	V _{CCO} + 0.3	25% V _{CCO}	75% V _{CCO}	Note(5)	Note(5)
HSTL I_12	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCO} + 0.3	25% V _{CCO}	75% V _{CCO}	6.3	6.3
HSTL I ⁽²⁾	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCO} + 0.3	0.4	V _{CCO} - 0.4	8	-8
HSTL II ⁽²⁾	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCO} + 0.3	0.4	V _{CCO} - 0.4	16	-16
HSTL III ⁽²⁾	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCO} + 0.3	0.4	V _{CCO} - 0.4	24	-8
DIFF HSTL I ⁽²⁾	-0.3	50% V _{CCO} - 0.1	50% V _{CCO} + 0.1	V _{CCO} + 0.3	-	-	-	-
DIFF HSTL II ⁽²⁾	-0.3	50% V _{CCO} - 0.1	50% V _{CCO} + 0.1	V _{CCO} + 0.3	-	-	-	-
SSTL2 I	-0.3	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCO} + 0.3	V _{TT} - 0.61	V _{TT} + 0.61	8.1	-8.1
SSTL2 II	-0.3	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCO} + 0.3	V _{TT} - 0.81	V _{TT} + 0.81	16.2	-16.2
DIFF SSTL2 I	-0.3	50% V _{CCO} - 0.15	50% V _{CCO} + 0.15	V _{CCO} + 0.3	-	-	-	-
DIFF SSTL2 II	-0.3	50% V _{CCO} - 0.15	50% V _{CCO} + 0.15	V _{CCO} + 0.3	-	-	-	-
SSTL18 I	-0.3	V _{REF} - 0.125	V _{REF} + 0.125	V _{CCO} + 0.3	V _{TT} - 0.47	V _{TT} + 0.47	6.7	-6.7
SSTL18 II	-0.3	V _{REF} - 0.125	V _{REF} + 0.125	V _{CCO} + 0.3	V _{TT} - 0.60	V _{TT} + 0.60	13.4	-13.4
DIFF SSTL18 I	-0.3	50% V _{CCO} - 0.125	50% V _{CCO} + 0.125	V _{CCO} + 0.3	-	-	-	-
DIFF SSTL18 II	-0.3	50% V _{CCO} - 0.125	50% V _{CCO} + 0.125	V _{CCO} + 0.3	-	-	-	-
SSTL15	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCO} + 0.3	V _{TT} - 0.175	V _{TT} + 0.175	14.3	14.3

Notes:

1. Tested according to relevant specifications.
2. Applies to both 1.5V and 1.8V HSTL.
3. Using drive strengths of 2, 4, 6, 8, 12, 16, or 24 mA.
4. Using drive strengths of 2, 4, 6, 8, 12, or 16 mA.
5. Supported drive strengths of 2, 4, 6, or 8 mA.
6. For detailed interface specific DC voltage levels, see [UG361: Virtex-6 FPGA SelectIO Resources User Guide](#).

GTH Transceiver Switching Characteristics

Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further information.

Table 32: GTH Transceiver Maximum Data Rate and PLL Frequency Range

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate ⁽¹⁾	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

- Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	–	645	MHz
		-2 and -3 speed grades	150	–	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	20	μs

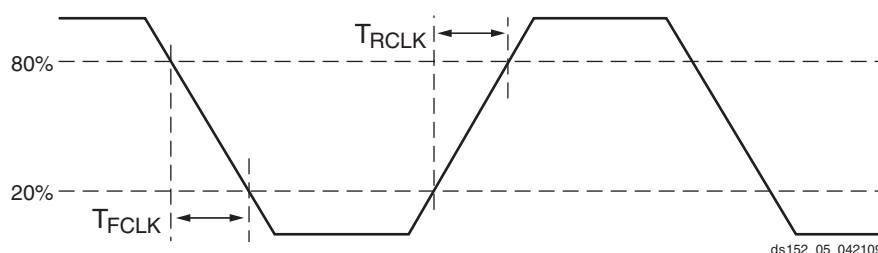


Figure 5: Reference Clock Timing Parameters

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:
<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$AV_{DD} = 2.5V \pm 5\%$, $V_{REFP} = 1.25V$, $V_{REFN} = 0V$, ADCCLK = 5.2 MHz, $T_j = -55^{\circ}C$ to $125^{\circ}C$ M-Grade, Typical values at $T_j=+35^{\circ}C$						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	–	–	Bits
Integral Nonlinearity	INL		–	–	± 1	LSBs
Differential Nonlinearity	DNL	No missing codes (T_{MIN} to T_{MAX}) Guaranteed Monotonic	–	–	± 0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	–	± 2	± 30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	–	± 2	± 30	LSBs
Gain Error		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 10	–	LSBs
		Deviation from ideal transfer function. Internal reference	–	± 20	–	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 1	± 2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	–	± 0.01	–	LSB/ $^{\circ}C$
DC Common-Mode Reject	CMRR _{DC}	$V_N = V_{CM} = 0.5V \pm 0.5V$, $V_P - V_N = 100mV$	–	70	–	dB
Conversion Rate⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	–	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	
T/H Acquisition Time	t _{Acq}	Number of CLK cycles	4	–	–	
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	5.2	MHz
CLK Duty cycle			40	–	60	%

Table 40: Analog-to-Digital Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
Analog Inputs⁽³⁾						
Dedicated Analog Inputs Input Voltage Range $V_P - V_N$ $T_j = -55^\circ\text{C}$ to 125°C		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	-0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	20	–	MHz
Auxiliary Analog Inputs Input Voltage Range $V_{\text{AUXP}[0]} / V_{\text{AUXN}[0]}$ to $V_{\text{AUXP}[15]} / V_{\text{AUXN}[15]}$ $T_j = -55^\circ\text{C}$ to 125°C		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	-0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	10	–	kHz
Input Leakage Current		A/D not converting, ADCCLK stopped	–	± 1.0	–	μA
Input Capacitance			–	10	–	pF
On-chip Supply Monitor Error		V_{CCINT} and V_{CCAUX} with calibration enabled. External 1.25V reference $T_j = -55^\circ\text{C}$ to 125°C .	–	–	± 1.0	% Reading
		V_{CCINT} and V_{CCAUX} with calibration enabled. Internal reference $T_j = -40^\circ\text{C}$ to 100°C . ⁽⁴⁾	–	± 2	–	% Reading
On-chip Temperature Monitor Error		$T_j = -55^\circ\text{C}$ to $+125^\circ\text{C}$ with calibration enabled. External 1.25V reference.	–	–	± 4	$^\circ\text{C}$
		$T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$ with calibration enabled. Internal reference. ⁽⁴⁾	–	± 5	–	$^\circ\text{C}$
External Reference Inputs⁽⁵⁾						
Positive Reference Input Voltage Range	V_{REFP}	Measured Relative to V_{REFN}	1.20	1.25	1.30	Volts
Negative Reference Input Voltage Range	V_{REFN}	Measured Relative to AGND	-50	0	100	mV
Input current	I_{REF}	ADCCLK = 5.2 MHz	–	–	100	μA
Power Requirements						
Analog Power Supply	AV_{DD}	Measured Relative to AV_{SS}	2.375	2.5	2.625	Volts
Analog Supply Current	AI_{DD}	ADCCLK = 5.2 MHz	–	–	12	mA

Notes:

- Offset errors are removed by enabling the System Monitor automatic gain calibration feature.
- See "System Monitor Timing" in [UG370: Virtex-6 FPGA System Monitor User Guide](#)
- See "Analog Inputs" in [UG370: Virtex-6 FPGA System Monitor User Guide](#) for a detailed description.
- These internal references are not specified over the junction temperature operating range for military (M) temperature devices.
- Any variation in the reference voltage from the nominal $V_{\text{REFP}} = 1.25\text{V}$ and $V_{\text{REFN}} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratio metric type applications allowing reference to vary by $\pm 4\%$ is permitted.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOP1}				T _{IOP2}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L		
LVCMOS25, Fast, 24 mA	0.51	0.57	0.66	0.70	1.66	1.79	1.99	1.96	1.66	1.79	1.99	1.96	ns	
LVCMOS18, Slow, 2 mA	0.55	0.61	0.71	0.73	4.21	4.47	4.87	4.30	4.21	4.47	4.87	4.30	ns	
LVCMOS18, Slow, 4 mA	0.55	0.61	0.71	0.73	2.79	2.96	3.21	2.94	2.79	2.96	3.21	2.94	ns	
LVCMOS18, Slow, 6 mA	0.55	0.61	0.71	0.73	2.30	2.43	2.64	2.47	2.30	2.43	2.64	2.47	ns	
LVCMOS18, Slow, 8 mA	0.55	0.61	0.71	0.73	2.01	2.11	2.27	2.24	2.01	2.11	2.27	2.24	ns	
LVCMOS18, Slow, 12 mA	0.55	0.61	0.71	0.73	1.88	1.99	2.15	2.10	1.88	1.99	2.15	2.10	ns	
LVCMOS18, Slow, 16 mA	0.55	0.61	0.71	0.73	1.84	1.95	2.11	2.04	1.84	1.95	2.11	2.04	ns	
LVCMOS18, Fast, 2 mA	0.55	0.61	0.71	0.73	4.00	4.23	4.57	4.08	4.00	4.23	4.57	4.08	ns	
LVCMOS18, Fast, 4 mA	0.55	0.61	0.71	0.73	2.62	2.76	2.97	2.74	2.62	2.76	2.97	2.74	ns	
LVCMOS18, Fast, 6 mA	0.55	0.61	0.71	0.73	2.15	2.28	2.46	2.32	2.15	2.28	2.46	2.32	ns	
LVCMOS18, Fast, 8 mA	0.55	0.61	0.71	0.73	1.90	1.99	2.13	2.14	1.90	1.99	2.13	2.14	ns	
LVCMOS18, Fast, 12 mA	0.55	0.61	0.71	0.73	1.69	1.80	1.97	1.88	1.69	1.80	1.97	1.88	ns	
LVCMOS18, Fast, 16 mA	0.55	0.61	0.71	0.73	1.63	1.74	1.91	1.88	1.63	1.74	1.91	1.88	ns	
LVCMOS15, Slow, 2 mA	0.64	0.73	0.85	0.85	3.43	3.77	4.29	3.91	3.43	3.77	4.29	3.91	ns	
LVCMOS15, Slow, 4 mA	0.64	0.73	0.85	0.85	2.58	2.79	3.10	2.93	2.58	2.79	3.10	2.93	ns	
LVCMOS15, Slow, 6 mA	0.64	0.73	0.85	0.85	2.08	2.32	2.68	2.50	2.08	2.32	2.68	2.50	ns	
LVCMOS15, Slow, 8 mA	0.64	0.73	0.85	0.85	1.81	1.98	2.23	2.24	1.81	1.98	2.23	2.24	ns	
LVCMOS15, Slow, 12 mA	0.64	0.73	0.85	0.85	1.76	1.91	2.13	2.07	1.76	1.91	2.13	2.07	ns	
LVCMOS15, Slow, 16 mA	0.64	0.73	0.85	0.85	1.69	1.83	2.04	1.98	1.69	1.83	2.04	1.98	ns	
LVCMOS15, Fast, 2 mA	0.64	0.73	0.85	0.85	3.44	3.77	4.28	3.91	3.44	3.77	4.28	3.91	ns	
LVCMOS15, Fast, 4 mA	0.64	0.73	0.85	0.85	2.37	2.53	2.78	2.66	2.37	2.53	2.78	2.66	ns	
LVCMOS15, Fast, 6 mA	0.64	0.73	0.85	0.85	1.80	2.05	2.42	2.16	1.80	2.05	2.42	2.16	ns	
LVCMOS15, Fast, 8 mA	0.64	0.73	0.85	0.85	1.76	1.90	2.11	2.04	1.76	1.90	2.11	2.04	ns	
LVCMOS15, Fast, 12 mA	0.64	0.73	0.85	0.85	1.64	1.77	1.97	1.90	1.64	1.77	1.97	1.90	ns	
LVCMOS15, Fast, 16 mA	0.64	0.73	0.85	0.85	1.62	1.76	1.96	1.92	1.62	1.76	1.96	1.92	ns	
LVCMOS12, Slow, 2 mA	0.72	0.81	0.93	0.95	3.14	3.39	3.75	3.54	3.14	3.39	3.75	3.54	ns	
LVCMOS12, Slow, 4 mA	0.72	0.81	0.93	0.95	2.43	2.63	2.93	2.79	2.43	2.63	2.93	2.79	ns	
LVCMOS12, Slow, 6 mA	0.72	0.81	0.93	0.95	1.92	2.11	2.41	2.26	1.92	2.11	2.41	2.26	ns	
LVCMOS12, Slow, 8 mA	0.72	0.81	0.93	0.95	1.87	2.02	2.25	2.17	1.87	2.02	2.25	2.17	ns	
LVCMOS12, Fast, 2 mA	0.72	0.81	0.93	0.95	2.71	2.98	3.39	3.11	2.71	2.98	3.39	3.11	ns	
LVCMOS12, Fast, 4 mA	0.72	0.81	0.93	0.95	1.93	2.16	2.51	2.31	1.93	2.16	2.51	2.31	ns	
LVCMOS12, Fast, 6 mA	0.72	0.81	0.93	0.95	1.75	1.89	2.11	2.05	1.75	1.89	2.11	2.05	ns	
LVCMOS12, Fast, 8 mA	0.72	0.81	0.93	0.95	1.69	1.82	2.02	1.98	1.69	1.82	2.02	1.98	ns	
LVDCI_25	0.51	0.57	0.66	0.70	2.05	2.14	2.26	2.26	2.05	2.14	2.26	2.26	ns	
LVDCI_18	0.55	0.61	0.71	0.73	2.07	2.23	2.47	2.38	2.07	2.23	2.47	2.38	ns	
LVDCI_15	0.64	0.73	0.85	0.85	1.85	2.01	2.24	2.18	1.85	2.01	2.24	2.18	ns	

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L		
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns	
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns	
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns	
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns	
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns	
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns	
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns	
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns	
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns	
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns	
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns	
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns	
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns	
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns	
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns	
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns	
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns	
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns	
LVCMOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns	
LVCMOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns	
LVCMOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns	
LVCMOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns	
LVCMOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns	
LVCMOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns	
LVCMOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns	
LVCMOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns	
LVCMOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns	
LVCMOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns	
LVCMOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns	
LVCMOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVCMOS25, Fast, 16 mA	0.57	0.66	0.70	1.92	2.15	2.08	1.92	2.15	2.08	ns	
LVCMOS25, Fast, 24 mA	0.57	0.66	0.70	1.79	2.15	1.96	1.79	2.15	1.96	ns	
LVCMOS18, Slow, 2 mA	0.61	0.71	0.73	4.47	4.87	4.30	4.47	4.87	4.30	ns	
LVCMOS18, Slow, 4 mA	0.61	0.71	0.73	2.96	3.21	2.94	2.96	3.21	2.94	ns	
LVCMOS18, Slow, 6 mA	0.61	0.71	0.73	2.43	2.64	2.47	2.43	2.64	2.47	ns	
LVCMOS18, Slow, 8 mA	0.61	0.71	0.73	2.11	2.41	2.24	2.11	2.41	2.24	ns	
LVCMOS18, Slow, 12 mA	0.61	0.71	0.73	1.99	2.30	2.10	1.99	2.30	2.10	ns	
LVCMOS18, Slow, 16 mA	0.61	0.71	0.73	1.95	2.30	2.04	1.95	2.30	2.04	ns	
LVCMOS18, Fast, 2 mA	0.61	0.71	0.73	4.23	4.57	4.08	4.23	4.57	4.08	ns	
LVCMOS18, Fast, 4 mA	0.61	0.71	0.73	2.76	2.97	2.74	2.76	2.97	2.74	ns	
LVCMOS18, Fast, 6 mA	0.61	0.71	0.73	2.28	2.46	2.32	2.28	2.46	2.32	ns	
LVCMOS18, Fast, 8 mA	0.61	0.71	0.73	1.99	2.34	2.14	1.99	2.34	2.14	ns	
LVCMOS18, Fast, 12 mA	0.61	0.71	0.73	1.80	2.19	1.88	1.80	2.19	1.88	ns	
LVCMOS18, Fast, 16 mA	0.61	0.71	0.73	1.74	2.18	1.88	1.74	2.18	1.88	ns	
LVCMOS15, Slow, 2 mA	0.73	0.85	0.85	3.77	4.29	3.91	3.77	4.29	3.91	ns	
LVCMOS15, Slow, 4 mA	0.73	0.85	0.85	2.79	3.10	2.93	2.79	3.10	2.93	ns	
LVCMOS15, Slow, 6 mA	0.73	0.85	0.85	2.32	2.68	2.50	2.32	2.68	2.50	ns	
LVCMOS15, Slow, 8 mA	0.73	0.85	0.85	1.98	2.29	2.24	1.98	2.29	2.24	ns	
LVCMOS15, Slow, 12 mA	0.73	0.85	0.85	1.91	2.23	2.07	1.91	2.23	2.07	ns	
LVCMOS15, Slow, 16 mA	0.73	0.85	0.85	1.83	2.23	1.98	1.83	2.23	1.98	ns	
LVCMOS15, Fast, 2 mA	0.73	0.85	0.85	3.77	4.28	3.91	3.77	4.28	3.91	ns	
LVCMOS15, Fast, 4 mA	0.73	0.85	0.85	2.53	2.78	2.66	2.53	2.78	2.66	ns	
LVCMOS15, Fast, 6 mA	0.73	0.85	0.85	2.05	2.42	2.16	2.05	2.42	2.16	ns	
LVCMOS15, Fast, 8 mA	0.73	0.85	0.85	1.90	2.20	2.04	1.90	2.20	2.04	ns	
LVCMOS15, Fast, 12 mA	0.73	0.85	0.85	1.77	2.11	1.90	1.77	2.11	1.90	ns	
LVCMOS15, Fast, 16 mA	0.73	0.85	0.85	1.76	2.11	1.92	1.76	2.11	1.92	ns	
LVCMOS12, Slow, 2 mA	0.81	0.93	0.95	3.39	3.75	3.54	3.39	3.75	3.54	ns	
LVCMOS12, Slow, 4 mA	0.81	0.93	0.95	2.63	2.93	2.79	2.63	2.93	2.79	ns	
LVCMOS12, Slow, 6 mA	0.81	0.93	0.95	2.11	2.67	2.26	2.11	2.67	2.26	ns	
LVCMOS12, Slow, 8 mA	0.81	0.93	0.95	2.02	2.25	2.17	2.02	2.25	2.17	ns	
LVCMOS12, Fast, 2 mA	0.81	0.93	0.95	2.98	3.39	3.11	2.98	3.39	3.11	ns	
LVCMOS12, Fast, 4 mA	0.81	0.93	0.95	2.16	2.70	2.31	2.16	2.70	2.31	ns	
LVCMOS12, Fast, 6 mA	0.81	0.93	0.95	1.89	2.34	2.05	1.89	2.34	2.05	ns	
LVCMOS12, Fast, 8 mA	0.81	0.93	0.95	1.82	2.10	1.98	1.82	2.10	1.98	ns	
LVDCI_25	0.57	0.70	0.70	2.14	2.82	2.26	2.14	2.82	2.26	ns	
LVDCI_18	0.61	0.71	0.73	2.23	2.78	2.38	2.23	2.78	2.38	ns	
LVDCI_15	0.73	0.85	0.85	2.01	2.75	2.18	2.01	2.75	2.18	ns	
LVDCI_DV2_25	0.57	0.70	0.70	1.83	2.37	2.00	1.83	2.37	2.00	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
DIFF_SSTL18_II	0.94	1.09	1.08	1.50	2.27	1.66	1.50	2.27	1.66	ns	
DIFF_SSTL18_II_DCI	0.94	1.09	1.08	1.47	2.20	1.62	1.47	2.20	1.62	ns	
DIFF_SSTL18_II_T_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns	
DIFF_SSTL15	0.91	1.06	1.06	1.54	2.25	1.69	1.54	2.25	1.69	ns	
DIFF_SSTL15_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns	
DIFF_SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns	

Table 46: IOB 3-state ON Output Switching Characteristics (T_{IOTPHZ})

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{IOTPHZ}	T input to Pad high-impedance	0.86	0.92	0.99	0.99	ns

Table 48: Output Delay Measurement Methodology (Cont'd)

Description	I/O Standard Attribute	R _{REF} (Ω)	C _{REF} ⁽¹⁾ (pF)	V _{MEAS} (V)	V _{REF} (V)
HT (HyperTransport), 2.5V	LDT_25	100	0	0 ⁽²⁾	0.6
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V	LVPECL_25	100	0	0 ⁽²⁾	0
LVDCI/HSLVDCI, 2.5V	LVDCI_25, HSLVDCI_25	1M	0	1.25	0
LVDCI/HSLVDCI, 1.8V	LVDCI_18, HSLVDCI_18	1M	0	0.9	0
LVDCI/HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I & II, with DCI	HSTL_I_DC1, HSTL_II_DC1	50	0	V _{REF}	0.75
HSTL, Class III, with DCI	HSTL_III_DC1	50	0	0.9	1.5
HSTL, Class I & II, 1.8V, with DCI	HSTL_I_DC1_18, HSTL_II_DC1_18	50	0	V _{REF}	0.9
HSTL, Class III, 1.8V, with DCI	HSTL_III_DC1_18	50	0	1.1	1.8
SSTL (Stub Series Termination Logic), Class I & II, 1.8V, with DCI	SSTL18_I_DC1, SSTL18_II_DC1	50	0	V _{REF}	0.9
SSTL, Class I & II, 2.5V, with DCI	SSTL2_I_DC1, SSTL2_II_DC1	50	0	V _{REF}	1.25

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 49: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Setup/Hold						
T _{ICE1CK/TICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.21/ 0.03	0.25/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T _{ISRCK/TICKSR}	SR pin Setup/Hold with respect to CLK	0.66/ -0.08	0.78/ -0.08	0.96/ -0.08	1.09/ -0.11	ns
T _{IDOCK/TILOCKD}	D pin Setup/Hold with respect to CLK without Delay	0.07/ 0.41	0.08/ 0.46	0.10/ 0.54	0.11/ 0.64	ns
T _{IDOCKD/TILOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)	0.10/ 0.32	0.12/ 0.36	0.14/ 0.42	0.16/ 0.50	ns
Combinatorial						
T _{IDI}	D pin to O pin propagation delay, no Delay	0.15	0.17	0.20	0.23	ns
T _{IDID}	DDLY pin to O pin propagation delay (using IODELAY)	0.19	0.22	0.25	0.28	ns
Sequential Delays						
T _{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.48	0.54	0.64	0.73	ns
T _{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY)	0.52	0.58	0.68	0.78	ns
T _{ICKQ}	CLK to Q outputs	0.54	0.61	0.70	0.93	ns
T _{RQ_ILOGIC}	SR pin to OQ/TQ out	0.85	0.97	1.15	1.32	ns
T _{GSRQ_ILOGIC}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	ns
Set/Reset						
T _{RPW_ILOGIC}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.30	ns, Min

Input/Output Delay Switching Characteristics

Table 53: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3.00	3.00	3.00	3.25	μs
F _{IDELAYCTRL_REF}	REFCLK frequency = 200.0 ⁽¹⁾	200	200	200	200	MHz
	REFCLK frequency = 300.0 ⁽¹⁾	300	300	—	—	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	50.00	50.00	50.00	52.50	ns
IODELAY						
T _{IDELAYRESOLUTION}	IODELAY Chain Delay Resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IODELAY_CLK_MAX}	Maximum frequency of CLK input to IODELAY	500.00	420.00	300.00	300.00	MHz
T _{IODCCK_CE} / T _{IODCKC_CE}	CE pin Setup/Hold with respect to CK	0.45/ -0.09	0.53/ -0.09	0.65/ -0.09	0.84/ -0.14	ns
T _{IODCK_INC} / T _{IODCKC_INC}	INC pin Setup/Hold with respect to CK	0.23/ -0.02	0.27/ -0.01	0.31/ 0.00	0.27/ -0.04	ns
T _{IODCCK_RST} / T _{IODCKC_RST}	RST pin Setup/Hold with respect to CK	0.57/ -0.08	0.62/ -0.08	0.69/ -0.08	0.74/ -0.13	ns
T _{IODDO_T}	TSCONTROL delay to MUXE/MUXF switching and through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_IDATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_ODATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IODELAY tap setting. See TRACE report for actual values.

CLB Switching Characteristics

Table 54: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Combinatorial Delays						
T _{IL0}	An – Dn LUT address to A	0.06	0.07	0.07	0.09	ns, Max
	An – Dn LUT address to AMUX/CMUX	0.18	0.20	0.22	0.25	ns, Max
	An – Dn LUT address to BMUX_A	0.28	0.31	0.36	0.40	ns, Max

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 55: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.92	1.10	1.36	1.49	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	1.19	1.40	1.71	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS/T_{DH}}	A – D inputs to CLK	0.62/0.18	0.72/0.20	0.88/0.22	0.98/0.23	ns, Min
T _{AS/T_{AH}}	Address An inputs to clock	0.19/0.52	0.22/0.59	0.27/0.66	0.30/0.75	ns, Min
T _{WS/T_{WH}}	WE input to clock	0.27/0.00	0.32/0.00	0.40/0.00	0.47–0.03	ns, Min
T _{CECK/T_{CKCE}}	CE input to CLK	0.28–0.01	0.34–0.01	0.41–0.01	0.48–0.05	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.70	0.82	1.00	1.04	ns, Min
T _{MCP}	Minimum clock period	1.40	1.64	2.00	2.08	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 56: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.11	1.30	1.58	1.74	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.37	1.60	1.93	2.12	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	1.08	1.27	1.55	1.74	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS/T_{WH}}	WE input	0.05/0.00	0.07/0.00	0.09/0.00	0.11/0.03	ns, Min
T _{CECK/T_{CKCE}}	CE input to CLK	0.06–0.01	0.08–0.01	0.10–0.01	0.12/0.02	ns, Min
T _{DS/T_{DH}}	A – D inputs to CLK	0.64/0.18	0.76/0.21	0.94/0.24	1.07/0.23	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.60	0.70	0.85	0.89	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

Block RAM and FIFO Switching Characteristics

Table 57: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.60	1.79	2.08	2.36	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.60	0.66	0.75	0.83	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.62	2.89	3.30	3.73	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.71	0.77	0.86	0.94	ns, Max
T _{RCKO_CASC} and T _{RCKO_CASC_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.49	2.77	3.18	3.61	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	1.29	1.41	1.58	1.79	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.74	0.81	0.91	0.98	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.90	0.98	1.09	1.21	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (with output register)	0.62	0.68	0.76	0.82	ns, Max
	Clock CLK to BITERR (without output register)	2.21	2.46	2.84	3.23	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.86	0.94	1.06	1.18	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.73	0.79	0.90	1.00	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.76	0.82	0.92	1.02	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDR} /T _{RCKC_ADDR}	ADDR inputs ⁽⁸⁾	0.47/ 0.27	0.53/ 0.29	0.62/ 0.32	0.66/ 0.34	ns, Min
T _{RDCK_DI} /T _{RCKD_DI}	DIN inputs ⁽⁹⁾	0.84/ 0.30	0.95/ 0.32	1.11/ 0.34	1.26/ 0.36	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.47/ 0.30	0.52/ 0.32	0.59/ 0.34	0.68/ 0.36	ns, Min
	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.68/ 0.30	0.75/ 0.32	0.85/ 0.34	0.97/ 0.36	ns, Min
	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.77/ 0.30	0.87/ 0.32	1.02/ 0.34	1.16/ 0.36	ns, Min
T _{RCKC_CLK} /T _{RCKC_CLK}	Inject single/double bit error in ECC mode	0.90/ 0.27	1.02/ 0.28	1.20/ 0.29	1.56/ 0.29	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	Block RAM Enable (EN) input	0.31/ 0.26	0.35/ 0.27	0.41/ 0.30	0.44/ 0.31	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.18/ 0.25	0.19/ 0.27	0.22/ 0.31	0.24/ 0.33	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/ 0.23	0.36/ 0.24	0.41/ 0.27	0.46/ 0.29	ns, Min

DSP48E1 Switching Characteristics

Table 58: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock							
$T_{DSPDCK_A, ACIN; B, BCIN}_AREG; BREG\}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{DSPCKD_A, ACIN; B, BCIN}_AREG; BREG\}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{DSPDCK_C_CREG}/T_{DSPCKD_C_CREG}$	C input to C register CLK	0.16/ 0.20	0.19/ 0.22	0.22/ 0.24	0.25/ 0.24	0.33/ 0.30	ns
$T_{DSPDCK_D_DREG}/T_{DSPCKD_D_DREG}$	D input to D register CLK	0.07/ 0.31	0.10/ 0.34	0.15/ 0.39	0.16/ 0.39	0.24/ 0.45	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock							
$T_{DSPDCK_A, ACIN, B, BCIN}_MREG_MULT\}$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{DSPCKD_A, ACIN, B, BCIN}_MREG_MULT\}$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{DSPDCK_A, D}_ADREG\}$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
$T_{DSPCKD_A, D}_ADREG\}$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock							
$T_{DSPDCK_A, ACIN, B, BCIN}_PREG_MULT\}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ -0.13	4.37/ -0.13	5.20/ -0.13	5.20/ -0.13	5.94/ -0.24	ns
$T_{DSPCKD_A, ACIN, B, BCIN}_PREG_MULT\}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ -0.13	4.37/ -0.13	5.20/ -0.13	5.20/ -0.13	5.94/ -0.24	ns
$T_{DSPDCK_D_PREG_MULT}/T_{DSPCKD_D_PREG_MULT}$	D input to P register CLK	3.62/ -0.47	4.13/ -0.47	4.90/ -0.47	4.90/ -0.47	5.61/ -0.77	ns
$T_{DSPDCK_A, ACIN, B, BCIN}_PREG\}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ -0.13	1.81/ -0.13	2.15/ -0.13	2.15/ -0.13	2.44/ -0.24	ns
$T_{DSPCKD_A, ACIN, B, BCIN}_PREG\}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ -0.13	1.81/ -0.13	2.15/ -0.13	2.15/ -0.13	2.44/ -0.24	ns
$T_{DSPDCK_C_PREG}/T_{DSPCKD_C_PREG}$	C input to P register CLK	1.42/ -0.10	1.61/ -0.10	1.91/ -0.10	1.91/ -0.10	2.16/ -0.19	ns
$T_{DSPDCK_PCIN, CARRYCASCIN, MULTSIGNIN}_PREG\}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ -0.02	1.41/ -0.02	1.67/ -0.02	1.67/ -0.02	1.91/ -0.07	ns
$T_{DSPCKD_PCIN, CARRYCASCIN, MULTSIGNIN}_PREG\}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ -0.02	1.41/ -0.02	1.67/ -0.02	1.67/ -0.02	1.91/ -0.07	ns
Setup and Hold Times of the CE Pins							
$T_{DSPDCK_CEA; CEB}_AREG; BREG\}$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{DSPCKD_CEA; CEB}_AREG; BREG\}$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{DSPDCK_CEC_CREG}/T_{DSPCKD_CEC_CREG}$	CEC input to C register CLK	0.15/ 0.18	0.18/ 0.20	0.24/ 0.23	0.24/ 0.23	0.31/ 0.26	ns
$T_{DSPDCK_CED_DREG}/T_{DSPCKD_CED_DREG}$	CED input to D register CLK	0.20/ 0.12	0.24/ 0.13	0.31/ 0.14	0.31/ 0.14	0.43/ 0.16	ns
$T_{DSPDCK_CEM_MREG}/T_{DSPCKD_CEM_MREG}$	CEM input to M register CLK	0.16/ 0.19	0.20/ 0.21	0.26/ 0.25	0.26/ 0.25	0.32/ 0.28	ns
$T_{DSPDCK_CEP_PREG}/T_{DSPCKD_CEP_PREG}$	CEP input to P register CLK	0.32/ 0.02	0.38/ 0.02	0.46/ 0.03	0.46/ 0.03	0.54/ 0.04	ns
Setup and Hold Times of the RST Pins							
$T_{DSPDCK_RSTA; RSTB}_AREG; BREG\}$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{DSPCKD_RSTA; RSTB}_AREG; BREG\}$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{DSPDCK_RSTC_CREG}/T_{DSPCKD_RSTC_CREG}$	RSTC input to C register CLK	0.18/ 0.08	0.20/ 0.08	0.23/ 0.09	0.23/ 0.09	0.27/ 0.11	ns
$T_{DSPDCK_RSTD_DREG}/T_{DSPCKD_RSTD_DREG}$	RSTD input to D register CLK	0.28/ 0.15	0.32/ 0.16	0.38/ 0.19	0.38/ 0.19	0.45/ 0.21	ns
$T_{DSPDCK_RSTM_MREG}/T_{DSPCKD_RSTM_MREG}$	RSTM input to M register CLK	0.20/ 0.24	0.23/ 0.26	0.26/ 0.30	0.26/ 0.30	0.29/ 0.34	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
T _{DSPDO_{PCIN, CARRYCASCIN, MULTSIGNIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}}	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
Clock to Outs from Output Register Clock to Output Pins							
T _{DSPCKO_{P, CARRYOUT}_PREG}	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_PREG}	CLK (PREG) to {CARRYCASOUT, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
Clock to Outs from Pipeline Register Clock to Output Pins							
T _{DSPCKO_{P, CARRYOUT}_MREG}	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MREG}	CLK (MREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
T _{DSPCKO_{P, CARRYOUT}_ADREG_MULT}	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_ADREG_MULT}	CLK (ADREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
Clock to Outs from Input Register Clock to Output Pins							
T _{DSPCKO_{P, CARRYOUT}_{AREG, BREG}_MULT}	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
T _{DSPCKO_{P, CARRYOUT}_{AREG, BREG}}	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
T _{DSPCKO_{P, CARRYOUT}_CREG}	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
T _{DSPCKO_{P, CARRYOUT}_DREG_MULT}	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
Clock to Outs from Input Register Clock to Cascading Output Pins							
T _{DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}}	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_{AREG, BREG}_MULT}	CLK (AREG, BREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_{AREG, BREG}}	CLK (AREG, BREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_DREG_MULT}	CLK (DREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
T _{DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_CREG}	CLK (CREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T_{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
F_{SMCCK}	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
F_{RBCK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
$F_{MCCKTOL}$	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
Boundary-Scan Port Timing Specifications						
$T_{TAP TCK}/T_{TCK TAP}$	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
$T_{TCK TDO}$	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
F_{TCK}	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
F_{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
F_{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
BPI Master Flash Mode Programming Switching						
$T_{BPICCO}^{(2)}$	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
T_{BPIDCC}/T_{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
$T_{INITADDR}$	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching						
$T_{SPIDCC}/T_{SPIDCCD}$	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
T_{SPICCM}	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
$T_{SPICCFc}$	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
$T_{FSINIT}/T_{FSINITH}$	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	μs
CCLK Output (Master Modes)						
T_{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
T_{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
CCLK Input (Slave Modes)						
T_{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
T_{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
F_{DCK}	Maximum frequency for DCLK	200	200	200	200	MHz
$T_{MMCMDCK_DADDR}/T_{MMCMCKD_DADDR}$	DADDR Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns

Table 64: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
RST _{MINPULSE}	Minimum Reset Pulse Width	1.5	1.5	1.5	1.5	ns
F _{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized ⁽⁹⁾	550	500	450	450	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300	300	300	300	MHz
F _{PFDMIN}	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	135	135	135	135	MHz
	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	10	10	10	10	MHz
T _{FBDELAY}	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
T _{MMCMDCK_PSEN} /T _{MMCMCKD_PSEN}	Setup and Hold of Phase Shift Enable	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMDCK_PSINCDEC} /T _{MMCMCKD_PSINCDEC}	Setup and Hold of Phase Shift Increment/Decrement	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMCKO_PSDONE}	Phase Shift Clock-to-Out of PSDONE	0.32	0.34	0.38	0.38	ns

Notes:

- When DIVCLK_DIVIDE = 3 or 4, F_{INMAX} is 315 MHz.
- This duty cycle specification does not apply to the GTH_QUAD (GTH) to MMCM connection. The GTH transceivers drive the MMCMs at the following maximum frequencies: 323 MHz for -1 speed grade devices, 350 MHz for -2 speed grade devices, or 350 MHz for -3 speed grade devices.
- The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
- The static offset is measured between any MMCM outputs with identical phase.
- Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
- Includes global clock buffer.
- Calculated as F_{VCO}/128 assuming output duty cycle is 50%.
- When CASCADE4_OUT = TRUE, F_{OUTMIN} is 0.036 MHz.
- In ISE software 12.3 (or earlier versions supporting the Virtex-6 family), the phase frequency detector Optimized bandwidth setting is equivalent to the High bandwidth setting. Starting with ISE software 12.4, the Optimized bandwidth setting is automatically adjusted to Low when the software can determine that the phase frequency detector input is less than 135 MHz.

Table 66: Global Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.							
T _C KOFMMCMGC	Global Clock Input and OUTFF <i>with</i> MMCM	XC6VLX75T	2.34	2.50	2.77	2.85	ns
		XC6VLX130T	2.35	2.51	2.78	2.87	ns
		XC6VLX195T	2.36	2.52	2.79	2.88	ns
		XC6VLX240T	2.36	2.52	2.79	2.88	ns
		XC6VLX365T	2.37	2.53	2.79	2.89	ns
		XC6VLX550T	N/A	2.55	2.82	2.93	ns
		XC6VLX760	N/A	2.54	2.82	2.92	ns
		XC6VSX315T	2.35	2.51	2.79	2.87	ns
		XC6VSX475T	N/A	2.43	2.70	2.79	ns
		XC6VHX250T	2.36	2.53	2.80	N/A	ns
		XC6VHX255T	2.46	2.63	2.91	N/A	ns
		XC6VHX380T	2.39	2.59	2.83	N/A	ns
		XC6VHX565T	N/A	2.54	2.81	N/A	ns
		XQ6VLX130T	N/A	2.51	2.78	2.87	ns
		XQ6VLX240T	N/A	2.52	2.79	2.88	ns
		XQ6VLX550T	N/A	N/A	2.82	2.93	ns
		XQ6VSX315T	N/A	2.51	2.79	2.87	ns
		XQ6VSX475T	N/A	N/A	2.70	2.79	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 73: Sample Window

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T _{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	All	510	560	610	670	ps
T _{SAMP_BUFI0}	Sampling Error at Receiver Pins using BUFI0 ⁽²⁾	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFI0 clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: Pin-to-Pin Setup/Hold and Clock-to-Out

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFI0						
T _{PSCS/T_{PHCS}}	Setup/Hold of I/O clock	-0.28/1.09	-0.28/1.16	-0.28/1.33	-0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFI0						
T _{CLOCKOFCS}	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V _{CCAUX} and V _{IN} numbers in Table 2, page 2 . Removed empty column from Table 3, page 3 . Revised specifications on Table 20, page 13 . Updated Table 38, page 22 and added notes 1 and 2. Revised T _{DLYCCO_RDY} , T _{IDELAYCTRL_RPW} , and T _{IDELAYPAT_JIT} in Table 53, page 41 . Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T _{TAPTCK/TCKTAP} in Table 59, page 49 . Updated XC6VLX130T parameters in Table 68 through Table 70, page 59 .
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V _{FS} and notes to Table 1 and Table 2 . Removed DV _{PPIN} from the example in Figure 2 . Added networking applications to Table 41, page 25 . Changed and added to the block RAM F _{MAX} section in Table 57, page 44 including removing Note 12. Changed F _{PFDMAX} values and corrected units for T _{STATPHAOFFSET} and T _{OUTDUTY} in Table 64, page 52 . Updated Table 71, page 60 .
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications . Updated speed specifications as described in Switching Characteristics , includes changes in Table 51 , Table 57 , Table 58 , and Table 66 through Table 70 . Comprehensive changes to Table 14 , Table 15 , and Table 16 . Added conditions to DV _{PPOUT} and revised description of T _{OSKEW} in Table 17 . Removed V _{ISE} specification and note from Table 18 . Added note 3 to Table 23 . Updated note 3 in Table 24 . Updated LVCMOS25 delays in Table 44 . Updated specification for T _{IOTPHZ} in Table 46 . Removed T _{BUFHSKREW} from Table 71, page 60 and added values for T _{BUFIOSKEW} . Added values in Table 74 .

Date	Version	Description of Revisions
02/08/11	2.12	Removed note 1 from Table 4 as the larger devices (XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX565T) are now offered in -2L. Updated Table 4 and Table 5 with data for the XC6VHX380T in the FF(G)1154 package. In Table 41 , updated -1L specification for DDR3. Added Note 1 to Table 42 . Moved the XC6VHX380T devices in the FF(G)1154 package to production release in Table 43 using ISE 12.4 software with current speed specifications. Updated description for F_{INDUTY} in Table 64 .
02/25/11	3.0	Designated the data sheet as Preliminary for all devices not already labeled production in Table 42 . Changed the XC6VHX380T devices in all packages to production status in Table 42 and Table 43 . Removed note 1 from Table 42 . Added maximum specifications to Table 25 . Updated $T_{HAVCC2HAVCCRX}$ in Table 27 . Updated the typical values and notes in Table 28 and Table 29 . Added values to Table 30 and Table 31 . In Table 34 , added values for T_{LOCK} and T_{PHASE} . Updated the values in Table 36 and added note 3. Updated Table 37 and added note 4.
03/21/11	3.1	Updated Table 2 including Note 7 . In Table 4 , added Note 3 and -2E, extended temperature range to the XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX380T devices, and added Note 5 for the XC6VHX565T. Updated Table 28 typical values. Updated the description for $F_{IDELAYCTRL_REF}$ in Table 53 . Updated F_{MCCK} in Table 59 .
04/01/11	3.2	Added T_j values for C, E, and I temperature ranges to Table 2 . Updated the I_{CCQ} values in Table 4 . Updated F_{GCLK} in Table 34 . Designated the data sheet as Production for all devices not already labeled production in Table 42 . Changed the XC6VHX255T and XC6VHX565T devices in all packages to production status in Table 42 and Table 43 . This included updates to the Virtex-6 Device Pin-to-Pin Output Parameter Guidelines and Virtex-6 Device Pin-to-Pin Input Parameter Guidelines for these devices. Production speed specifications for these devices are available using the speed specification v1.14 in the ISE 13.1 software update. Updated and added package skew values to Table 72 ; these values are correct with regards to previous production released speed specifications in software. Updated copyright page 1 and Notice of Disclaimer .
12/08/11	3.3	Production release of the Defense-grade XQ devices in Table 42 and Table 43 using ISE v13.3 v1.17 Patch for -2 and -1 speed specifications; and v1.10 for -1L speed specifications. Added the XQ6VLX130T, XQ6VLX240T, XQ6VLX550T, XQ6VSX315T, and XQ6VSX475T to the data sheet which included adding Table 45 . Updated T_j in Table 2 . In Table 40 , updated T_j for most specifications and added Note 4 . Added Note 4 to Table 41 . Added -1(XQ) speed specification columns only to Table 50 , Table 51 , Table 52 , and Table 58 . Updated V_{OD} in Table 8 , V_{OCM} in Table 9 , and V_{OCM} and V_{DIFF} in Table 10 . Updated the Power-On Power Supply Requirements section. In Table 27 , updated maximum specification for $T_{HAVCC2HAVCCRX}$ and added Note 3 . Updated T_j in Table 40 . In Table 41 , increased the DDR LVDS receiver (SPI-4.2) -1 speed grade performance value from 1.0 Gb/s to 1.1 Gb/s. In Table 60 , updated the F_{MAX} to add a separate row for the LX760 device values. The speed specifications in the software tools have always matched these values for the LX760, the data sheet is now correct. Updated the notes for $T_{OUTJITTER}$ in Table 64 .
01/12/12	3.4	Added the temperature range -2E to Note 5 in Table 4 .